



Super Sharp Probes+Single Crystal Diamond Tip-Topography Measurements

SSP-SCDT-TM

AFM Nanoprobes offers unique probes with single crystal diamond probes for topography, conductive measurements, and electrical measurements. These long-lasting, and highly conductive, sharp diamond probes are highly resistant to mechanical destruction and keep their sharpness. They enable highly repeatable, high resolution operation to ensure you consistently get the best possible data from your system. Single crystal diamond probes are formed by a unique patented process to ensure the best possible wear and electrical performance. The probes are sharper and last longer than any other electrical AFM probe.

SPECIFICATIONS

short_desc	Unique Super Sharp Probes with Single Crystal Diamond Tip for Topography Measurements
Categories	AFM Probes, Diamond
Tags	: General Topography, Hardened/Enhanced Wear Resistance
Quantity	5
Cantilever Length	225
Cantilever Width	35
Cantilever Thickness	3.8
Resonant Frequency [kHz]	100, 180, 260
Force Constant [N/m]	20, 40, 60
Coating	Au Reflective
Cantilever Shape	Rectangular
Cantilever	Single
Tip	Conical
Tip Material	Single Crystal Diamond highly doped with Boron

Shop online at afm-nanoprobes.cd-bioparticles.net or contact us at:

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